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## Journal of Research of the

# National Institute of Standards and Technology



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- Materials Reliability<sup>1</sup>
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- · Advanced Network Technologies
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- High Performance Systems and Services
- Distributed Computing and Information Services
- Software Diagnostics and Conformance Testing

<sup>&</sup>lt;sup>2</sup>Some elements at Boulder, CO.

## Journal of Research of the National Institute of Standards and Technology

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